


<b>Search Notes</b>  	<b>Application/Control No.</b>  10638397	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG, LIN-WEI
	<b>Examiner</b>  Kosowski, Alexander J	<b>Art Unit</b>  2125

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
700	90	12/20/07	AJK
361	685,727		

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST Search (attached)	12/20/07	AJK
EIC TC2100 PLUS Search		
Consulted Primary Examiner in AU2835 for search assistance		
PALM Inventor Name Search		

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>